## STW40N95K5



# N-channel 950 V, 0.110 Ω typ., 38 A MDmesh™ K5 Power MOSFET in a TO-247 package

Datasheet - production data

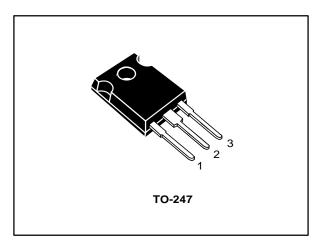
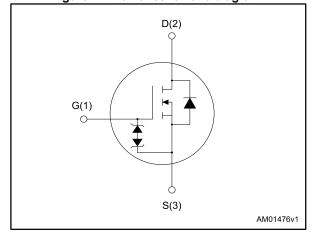


Figure 1: Internal schematic diagram



#### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max	ΙD	Ртот
STW40N95K5	950 V	0.130 Ω	38 A	450 W

- Industry's lowest R<sub>DS(on)</sub> x area
- Industry's best figure of merit (FoM)
- Ultra low gate charge
- 100% avalanche tested
- Zener-protected

### **Applications**

• Switching applications

### **Description**

This very high voltage N-channel Power MOSFET is designed using MDmesh™ K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

**Table 1: Device summary** 

Order code	Marking	Package	Packaging
STW40N95K5	40N95K5	TO-247	Tube

Contents STW40N95K5

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STW40N95K5 Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>GS</sub>	Gate- source voltage	± 30	V
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25 °C	38	Α
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100 °C	24	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	152	Α
Ртот	Total dissipation at T <sub>C</sub> = 25 °C		W
I <sub>AR</sub>	Max current during repetitive or single pulse avalanche	13	Α
Eas	Single pulse avalanche energy (starting T <sub>J</sub> = 25 °C, I <sub>D</sub> = 13 A, V <sub>DD</sub> = 50 V)		mJ
dv/dt (2)	Peak diode recovery voltage slope	4.5	V/ns
dv/dt (3)	MOSFET dv/dt ruggedness 50		V/ns
T <sub>j</sub> T <sub>stg</sub>	Operating junction temperature Storage temperature	-55 to 150	°C

#### Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	0.28	°C/W
R <sub>thj-amb</sub>	R <sub>thj-amb</sub> Thermal resistance junction-amb max		°C/W

<sup>&</sup>lt;sup>(1)</sup>Pulse width limited by safe operating area.

 $<sup>^{(2)}</sup>I_{SD} \leq$  19 A, di/dt  $\leq$  100 A/ $\mu$ s, VDS(peak)  $\leq$  V(BR)DSS.

 $<sup>^{(3)}</sup>V_{DS} \le 760 \text{ V}$ 

Electrical characteristics STW40N95K5

### 2 Electrical characteristics

(T<sub>case</sub> =25 °C unless otherwise specified)

Table 4: On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	V <sub>GS</sub> = 0, I <sub>D</sub> = 1 mA	950			٧
	Zara gata valtaga drain	V <sub>GS</sub> = 0, V <sub>DS</sub> = 950 V			1	μΑ
IDSS	Zero gate voltage drain current	V <sub>GS</sub> = 0, V <sub>DS</sub> = 950 V, T <sub>C</sub> =125 °C			50	μΑ
Igss	Gate-body leakage current	$V_{DS}=0, V_{GS}=\pm 20 \text{ V}$			±10	μΑ
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 100 \mu A$	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on- resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 19 A		0.110	0.130	Ω

Table 5: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	3300	•	pF
Coss	Output capacitance	V <sub>GS</sub> =0, V <sub>DS</sub> =100 V, f=1 MHz	-	250	ı	pF
Crss	Reverse transfer capacitance	V33-0, V53-100 V, 1-1 WHZ	-	2	ı	pF
C <sub>o(tr)</sub> (1)	Equivalent capacitance time related	$V_{GS} = 0$ , $V_{DS} = 0$ to 760 V	-	398	ı	pF
C <sub>o(er)</sub> <sup>(2)</sup>	Equivalent capacitance energy related	V <sub>GS</sub> = 0, V <sub>DS</sub> = 0 to 760 V	-	142	1	pF
R <sub>G</sub>	Intrinsic gate resistance	f = 1 MHz, I <sub>D</sub> =0	-	5	ı	Ω
$Q_g$	Total gate charge	$V_{DD} = 760 \text{ V}, I_D = 38 \text{ A}$	-	93	•	nC
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> =10 V	-	18.7	-	nC
Q <sub>gd</sub>	Gate-drain charge	(see Figure 16: "Gate charge test circuit")	-	63.4	ı	nC

#### Notes

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Table 6: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t <sub>d(on)</sub>	Turn-on delay time	V <sub>DD</sub> = 475 V, I <sub>D</sub> = 19 A,	-	33.5	-	ns
tr	Rise time	$R_G = 4.7 \Omega$ , $V_{GS} = 10 V$	ı	51	1	ns
t <sub>d(off)</sub>	Turn-off-delay time	(see Figure 15: "Switching times test circuit for resistive load")	- 1	91.5	ı	ns
t <sub>f</sub>	Fall time		-	10	-	ns

 $<sup>^{(1)}</sup>$ Time related is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 

 $<sup>^{(2)}</sup>$ energy related is defined as a constant equivalent capacitance giving the same stored energy as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 

Table 7: Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
I <sub>SD</sub>	Source-drain current		-		38	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		1		152	Α
V <sub>SD</sub> (2)	Forward on voltage	I <sub>SD</sub> = 38 A, V <sub>GS</sub> = 0	-		1.5	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 38 A, di/dt = 100 A/µs	-	706		ns
Qrr	Reverse recovery charge	V <sub>DD</sub> = 60 V (see Figure 18: " Unclamped inductive load test circuit")	-	22		μC
I <sub>RRM</sub>	Reverse recovery current		-	62		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 38 A, di/dt = 100 A/µs V <sub>DD</sub> = 60 V T <sub>J</sub> = 150 °C (see <i>Figure 18: " Unclamped</i>	-	886		ns
Qrr	Reverse recovery charge		-	28.2		μC
I <sub>RRM</sub>	Reverse recovery current	inductive load test circuit")		64		А

#### Notes:

**Table 8: Gate-source Zener diode** 

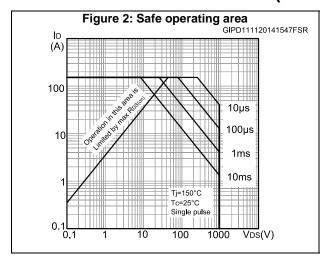
Symbol	Parameter	Test conditions	Min	Тур.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1 \text{mA}, I_{D}=0$	30	-	1	V

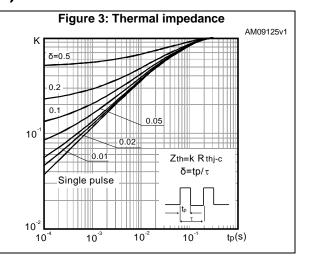
The built-in back-to-back Zener diodes have specifically been designed to enhance the device's ESD capability. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

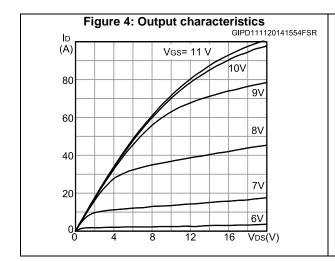
<sup>&</sup>lt;sup>(1)</sup>Pulse width limited by safe operating area.

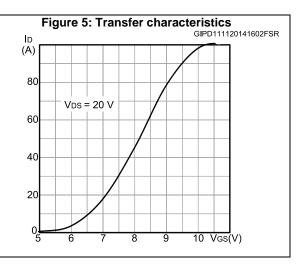
 $<sup>^{(2)}</sup>$ Pulsed: pulse duration = 300  $\mu$ s, duty cycle 1.5%

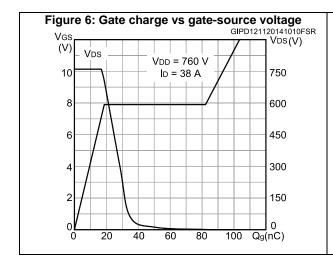
# 2.1 Electrical characteristics (curves)

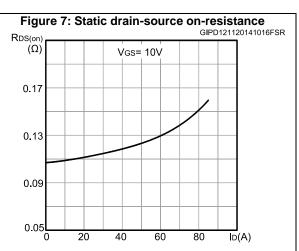












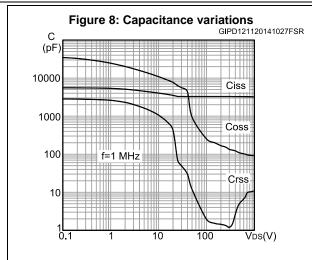
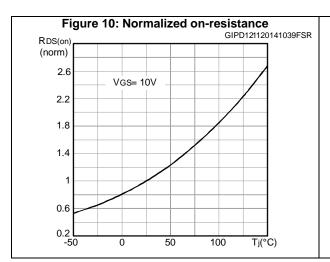
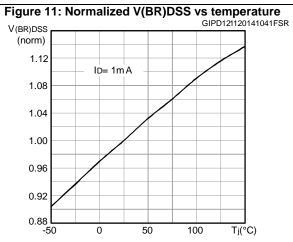
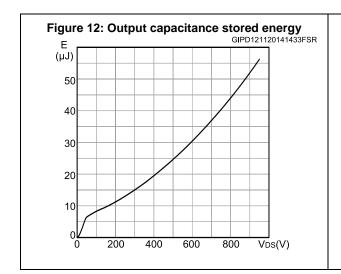
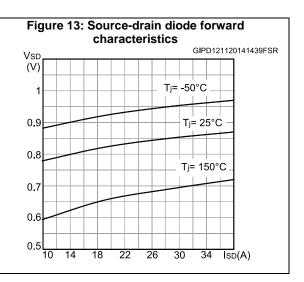


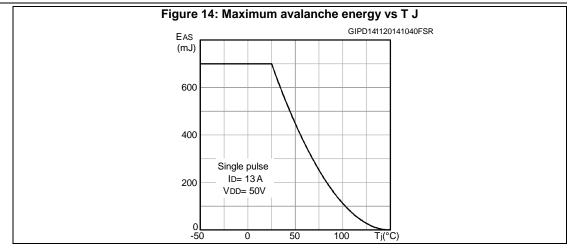
Figure 9: Normalized gate threshold voltage vs temperature GIPD121120141035FSR VGS(th) (norm) ID = 100 μA 1.2 1.0 0.8 0.6 0.4 0.2 -50 0 50 100 Tj(°C)





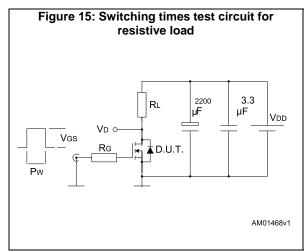






STW40N95K5 Test circuits

### 3 Test circuits



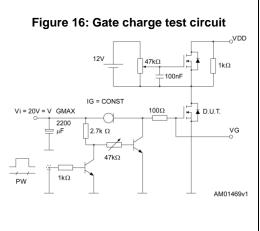
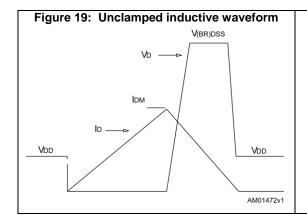


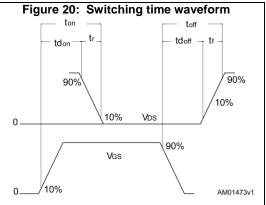
Figure 18: Unclamped inductive load test circuit

VD 0 2200 3.3 JF VDD

ND D.U.T.

AM01471v1





## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

## 4.1 TO-247 package information

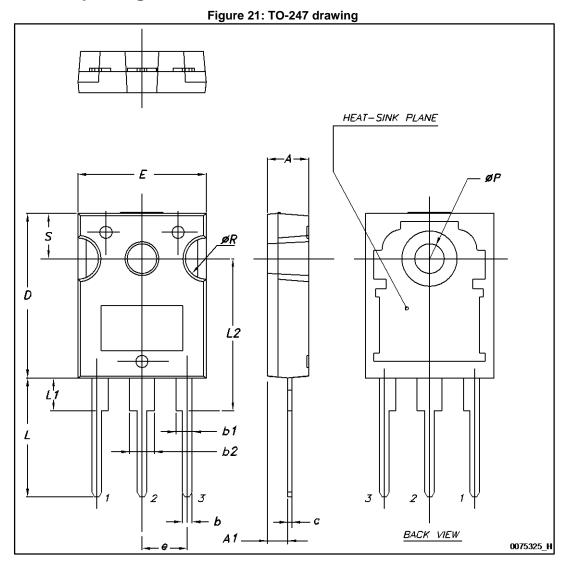


Table 9: TO-247 mechanical data

Dim	mm.				
Dim.	Min.	Тур.	Max.		
А	4.85		5.15		
A1	2.20		2.60		
b	1.0		1.40		
b1	2.0		2.40		
b2	3.0		3.40		
С	0.40		0.80		
D	19.85		20.15		
E	15.45		15.75		
е	5.30	5.45	5.60		
L	14.20		14.80		
L1	3.70		4.30		
L2		18.50			
ØP	3.55		3.65		
ØR	4.50		5.50		
S	5.30	5.50	5.70		



Revision history STW40N95K5

## 5 Revision history

**Table 10: Document revision history** 

Date	Revision	Changes	
03-Jun-2014	1	First release.	
14-Nov-2014	2	Document status promoted from preliminary to production data.  Added Section 2.1: "Electrical characteristics (curves)".	

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